

Efficient Adaptive Hold Logic Reliable Multiplier Using Variable Latency Design

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Abstract - High speed and low power consumption is one of the most important design objectives in integrated circuits. Digital multipliers are most critical functional units. The overall performance of these system depends on the throughput of multiplier design. Aging problem of transistors has a significant effect on performance of these systems and in long term, the system may fail due to timing violations. Aging effect can be reduced by using over-design approaches, but these leads to area, power inefficiency. Hence to reduce the maximum power consumption and delay, variable latency multiplier with adaptive hold logic is used. The multiplier is able to provide higher throughput through the variable latency and can adjust the AHL circuit to mitigate performance degradation that is due to the aging effect. The proposed architecture can be applied to image multiplication. Based on the idea of razor flip flop and adaptive hold logic the timing violations are reduced. In the fixed latency usage of clock cycles is increased. The reexecution of clock cycles is reduced by using variable latency.

Index Terms - Adaptive hold logic; Negative bias temperature instability; Variable latency ; Fixed latency

I. INTRODUCTION

Multiplication is an essential arithmetic operation for common DSP applications, such as filtering and fast Fourier transform (FFT). To achieve high execution speed, parallel array multipliers are widely used. These multipliers tend to consume most of the power in DSP computations, and thus power-efficient multipliers are very important for the design of low-power DSP systems. If the multipliers are too slow, the performance of entire circuits will be reduced.

Traditional circuits use critical path delay as the overall circuit clock cycle in order to perform correctly. Hence, the variable-latency design was proposed to reduce the timing waste of traditional circuits. The variable-latency design divides the circuit into two parts they are shorter paths and longer paths. Shorter paths can execute correctly in one cycle, whereas longer paths need two cycles to execute. When shorter paths are activated frequently, the average latency of variable-latency designs is better than that of traditional designs. It is well known that multipliers consume most of the power in DSP computations. In this paper, we presents low power Column bypass multiplier and row bypass multiplier design methodology that inserts more number of zeros in the multiplicand and multiplier thereby reducing the number of delay as well as power consumption. The delay and power are

reduction are depends on the input bit coefficient. This means if the input bit coefficient is zero, corresponding row or column of adders need not be activated. Negative bias temperature instability (NBTI) occurs when a PMOS transistor is under negative bias, results in aging effect. Aging effect degrades transistor speed by increase in threshold voltage, which results in real time delay problems. The corresponding effect on an nMOS transistor is positive bias temperature instability (PBTI), which occurs when an nMOS transistor is under positive bias. Traditional methods to reduce this aging effect were area and power inefficient.

In variable- latency design, shortest paths are assigned to be executed within one cycle and longest paths within two or more cycle. When shorter paths are activated frequently, the average latency of variable-latency designs is better than that of fixed latency designs. The main objective of the work is to multiply two images using low power variable latency multiplier with AH logic. The coding can be synthesized by the Xilinx ISE Design Suite, simulated using Model-Sim simulator. The major application of these digital multiplier are in the field of digital filtering and signal processing.

II. IMPACT OF NBTI ON THE PERFORMANCE DEGRADATION OF DIGITAL CIRCUITS

NBTI is a major side effect on the lifetime reliability of integrated circuits. With the continuous scaling of transistor dimensions, the reliability degradation of circuits has become an important issue. Due to an increasing electric field across the thin oxide, the generation of interface traps under negative bias temperature instability (NBTI) in pMOS transistors has become one of the most critical reliability issues that determine the lifetime of CMOS devices. Due to NBTI, the threshold voltage of the transistor increases with time resulting in the reduction in drive current, which in turn results in temporal performance degradation of circuits.

Vth Degradation Model: NBTI is the result of trap generation at Si/SiO interface in negatively based PMOS transistors at elevated temperatures. The interaction of inversion layer holes with hydrogen passivated Si atoms can break the SiH bonds, creating an interface trap and one H atom that can diffuse away from the interface or can anneal an existing trap.

Gate Delay Degradation Model: Delay of gate depends on threshold voltage value. Therefore, by monitoring the threshold voltage degradation, the change in gate delay can be easily estimated with a high degree of accuracy.

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From the above analysis, it is clear that circuit delay depends on threshold voltage variation and hence performance degradation will occur. Various techniques used to mitigate this effect is Vdd tuning, PMOS sizing, Tuning of gate length and Tuning of switching frequency. By this techniques we can reduce NBTI to a greater extend but area, power inefficiency is a major problem.

III. BYPASSING TECHNIQUE

Dynamic power consumption can be reduced by bypassing method when the multiplier has more zeros in input data. To perform isolation, transmission gates can be used, as ideal switches with small power consumption, propagation delay similar to the inverter and small area. To study the proposed design we have consider column bypassing multiplier in which columns of adders are bypassed. In this multiplier, the operations in a column can be disabled if the corresponding bit in the multiplicand is 0. The advantage of this multiplier is it eliminates the extra correcting circuit.

Bypassing multipliers are modification of normal array multipliers. Dynamic power consumption can be reduced by bypassing method when the multiplier has more zeros in input data. The path delay for an operation is strongly tied to the number of zeros in the multiplicands in the column- bypassing multiplier. The column bypassing multiplier (CBM) only needs two tristate gates and one multiplexer in a adder cell. Traditional filter design using bypassing multiplier does not consider variable latency technique. However, no digital FIR Filter using variable latency based multiplier that considers the aging effect and can adjust dynamically has yet been developed.

IV. METHODOLOGY

A) ARRAY MULTIPLIER

The array multiplier is a fast parallel multiplier and is shown in Fig.1 and it consists of (n-1) rows of carry save adder, in which each row contains (n-1) full adders. Each full adder in the carry save adder array has two outputs they are the sum bit goes down and the carry bit goes to the lower left full adder. The last row is a ripple adder for carry propagation

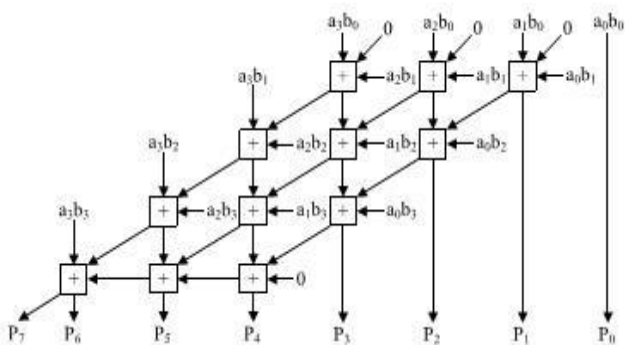


Fig. 1. Normal array multiplier

B) COLUMN BYPASSING MULTIPLIER

A column-bypassing multiplier is an improvement of the array multiplier and is shown in Fig.2. A low-power column-bypassing multiplier design is proposed in which the full adder operations are disabled if the corresponding bit in the multiplicand is zero. Supposing the inputs are 1010 * 1111, it can be seen that for the full adders in the first and third diagonals, two of the three input bits are 0 and the carry bit from its upper right full adder and the partial product $a_i b_i$.

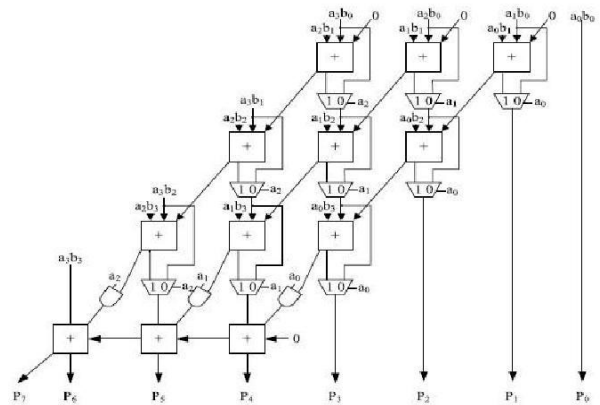


Fig.2. Column bypassing multiplier

The multiplicand bit a_i can be used as the selector of the multiplexer to decide the output of the full adder, and a_i can also be used as the selector of the tristate gate to turn off the input path of the full adder. If a_i is 0, the inputs of full adder are disabled, and the sum bit of the current full adder is equal to the sum bit from its upper full adder, thus reducing the power consumption of the multiplier. If a_i is 1, the normal sum result is selected.

C) Variable Latency Design

The variable-latency design was proposed to reduce the timing waste occurring in traditional circuits that use the critical path cycle as an execution cycle period. The basic concept is to execute a shorter path using a shorter cycle and longer path using two cycles. Since most paths execute in a cycle period that is much smaller than the critical path delay, the variable-latency design has smaller average latency.

D) Razor flip flop

Razor flip-flops can be used to detect whether timing violations occur before the next input pattern arrives. A 1-bit Razor flip-flop contains a main flip-flop, shadow latch, XOR gate, and multiplexer. The main flip-flop catches the execution result for the combination circuit using a normal clock signal, and the shadow latch catches the execution result using a delayed clock signal, which is slower than the normal clock signal. If the latched bit of the shadow latch is different from that of the main flip-flop, this means the path delay of the current operation exceeds the cycle period, and the main flip-flop catches an incorrect result. If errors occur, the Razor flip-flop will set the error signal to 1 to notify the system to reexecute the operation and notify the AHL circuit that an error has occurred.

E) Adaptive hold logic

The Adaptive Hold Logic circuit is the key component of variable-latency multiplier. The AHL circuit contains decision block, MUX and a D flip-flop. If the cycle period is too short, the column-bypassing multiplier is not able to complete these operations successfully, causing timing violations. These timing violations will be caught by the Razor flip-flops, which generate error signals. If errors happen frequently, it means the circuit has suffered significant timing degradation due to the aging effect.

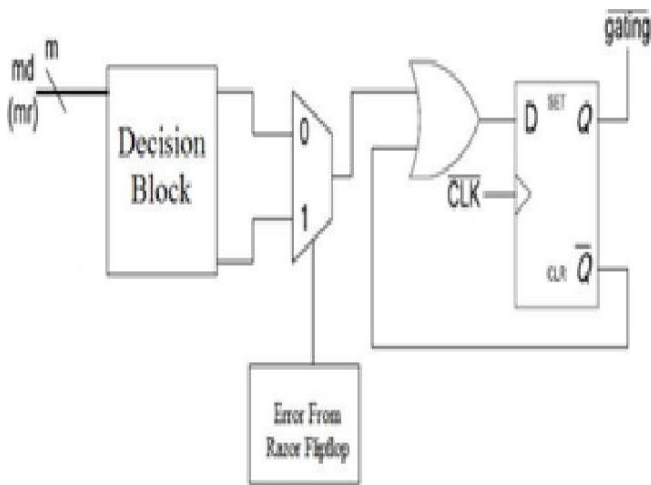


Fig.3. Adaptive hold logic

When an input pattern arrives, decision block will decide whether the pattern requires one cycle or two cycles to complete and pass both results to the multiplexer. The multiplexer selects one of either result based on the output of the razor flip-flop. Then an OR operation is performed between the result of the multiplexer, and the Q bar signal is used to determine the input of the D flip-flop. When the pattern requires one cycle, the output of the multiplexer is 1. The (gating) signal will become 1, and the input flip-flops will latch new data in the next cycle. On the other hand, when the output of the multiplexer is 0, which means the input pattern requires two cycles to complete, the OR gate will output 0 to the D flip-flop. Therefore, the (gating) signal will be 0 to disable the clock signal of the input flip-flops in the next cycle.

V. VARIABLE LATENCY MULTIPLIER DESIGN WITH AHL

Aging aware multiplier design includes two m-bit inputs (m is a positive number), one 2m-bit output, one column-bypassing multiplier, 2m 1-bit Razor flip-flops, and an AHL circuit. Clock is provided by the AND gate at the input.

When input patterns arrive, the column-bypassing multiplier and the AHL circuit execute simultaneously. Depending on the number of zeros in the multiplicand, the AHL circuit decides number of clock cycles required for the current input pattern. If the input pattern requires two cycles

to complete, the AHL will output 0 to disable the clock signal of the input flip-flops. Otherwise, the AHL will output 1 for normal operations.

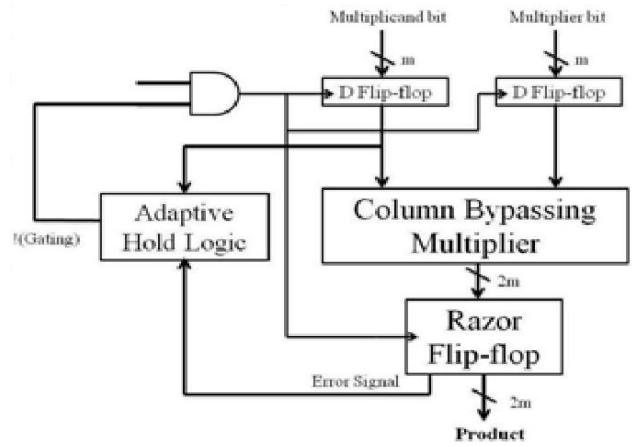


Fig.4. Variable latency multiplier with AHL

When the column bypassing multiplier completes the operation, the result will be passed to the Razor flip-flops. The Razor flip-flops check for any path delay timing violations. If timing violations occur, it means that the cycle period is not long enough for the current operation to complete and that the execution result of the multiplier is incorrect. Thus, the Razor flip-flops will output an error to inform the system that the current operation needs to be re-executed using two cycles to ensure the operation is correct.

VI. APPLICATION : IMAGE PROCESSING

In this section the application of the proposed multipliers to image processing is illustrated. A multiplier is used to multiply two images on a pixel by pixel basis, thus blending the two images into a single output image.

VII. RESULT AND DISCUSSION

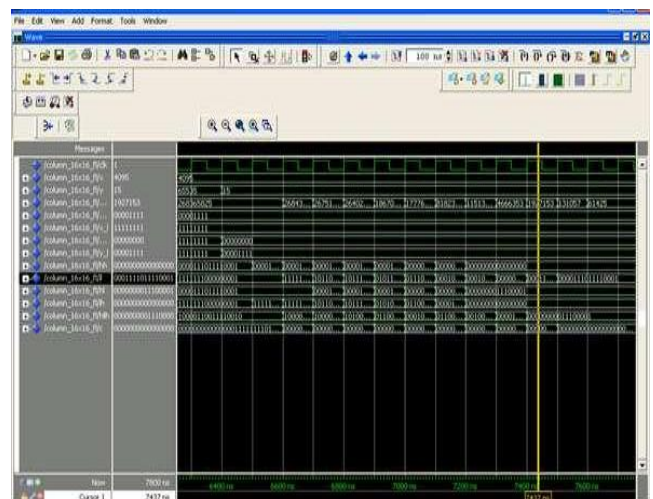


Fig.5. Simulation result of 16*16 fixed latency

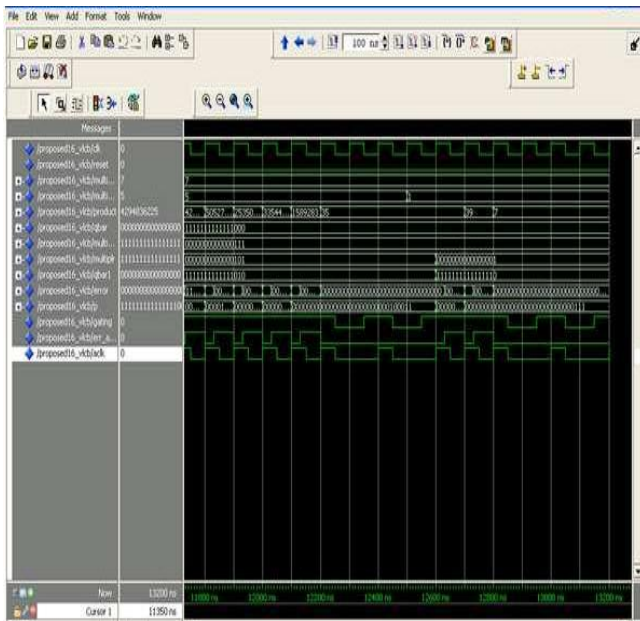


Fig.6. Simulation result of 16*16 variable latency

TABLE I
SIMULATION RESULT

Multiplier	PARAMETERS		
	Delay (ns)	Power (mW)	Area (Gate count)
Fixed latency	6.199	129	12,826
Variable latency	3.076	49	8,199

In the fixed latency the more number of clock cycle are required and due to which the area, power and delay are increased. In the variable latency lesser number of clock cycle are used, the error is reduced so that the area, power and delay are reduced.

VIII. CONCLUSION

Variable-latency design minimizes the timing waste of the noncritical paths. This multiplier is able to adjust the adaptive hold logic to mitigate performance degradation due to delay problems. Variable-latency design can adjust clock cycle required by input patterns. And hence variable latency multipliers have less performance degradation when compared with traditional fixed latency multipliers, which needs to consider the degradation by both the NBTI effect and use the worst case delay as the cycle period. This can be used as an application of image multiplication. We can multiply two images using low power variable latency multiplier with AH logic, can be enhanced by reduced delay, area and power.

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